

<b>Notice of References Cited</b>	Application/Control No. 10/581,256	Applicant(s)/Patent Under Reexamination OKUNE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nagata et al. (Japanese Journal of Applied Physics, Vol. 28, No. 11, November, 1989, pp. 2368-2371)
	V	Tzeng et al. (J. Electrochem. Soc. Vol. 134, No. 9, September 1987, pp. 2304-2309)
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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